

IGBT3 Chip

Features:

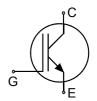
- 650V Trench & Field Stop technology
- low V_{CE(sat)}
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling
- Qualified according to JEDEC for target applications

Recommended for:

• power modules

Applications:

• drives



| Chip Type | V _{CE} | / Cn ¹⁾ | Die Size | Package |
|--------------|-----------------|---------------------------|-----------------------------|--------------|
| SIGC40T65R3E | 650V | 75A | 5.74 x 6.96 mm ² | sawn on foil |

¹⁾ nominal collector current at Tc = 100°C, not subject to production test - verified by design/characterization

Mechanical Parameters

| Meenamearranamet | | F | - | |
|-----------------------------------|----------------------------------|---|-----------------|--|
| Die size | | 5.74 x 6.96 | | |
| Emitter pad size (incl. gate pad) | | See chip drawing | mm ² | |
| Gate pad size | | 1.615 x 0.817 | mm | |
| Area total | | 39.95 | | |
| Thickness | | 70 | μm | |
| Wafer size | | 200 | mm | |
| Max.possible chips pe | er wafer | 666 | · | |
| Passivation frontside | | Photoimide | | |
| Pad metal | | 3200 nm AlSiCu | | |
| Backside metal | | Ni Ag –system | | |
| Die bond | | Electrically conductive epoxy glue and soft solder | | |
| Wire bond | | AI, <500µm | | |
| Reject ink dot size | | Ø 0.65mm ; max 1.2mm | | |
| | for original and sealed MBB bags | Ambient atmosphere air, Temperature 17°C – 2 < 6 month | | |
| Storage environment | for open MBB bags | Acc. to IEC62258-3: Atmosphere >99% Nitrogen of Humidity <25%RH, Temperature 17°C – 25°C, < | | |



Maximum Ratings

| Parameter | Symbol | Value | Unit |
|---|---------------------|----------|------|
| Collector-Emitter voltage, <i>T</i> _{vj} =25 °C | V _{CE} | 650 | V |
| DC collector current, limited by $T_{vj max}$ | I _c | 1) | А |
| Pulsed collector current, t_p limited by $T_{vj \max}^{2}$ | I _{c,puls} | 225 | А |
| Gate emitter voltage | V _{GE} | ±20 | V |
| Operating junction temperature | T _{vj} | -40 +175 | °C |
| Short circuit data ²) ³⁾ V_{GE} = 15V, V_{CC} = 360V, T_{vj} = 150°C | t _{sc} | 6 | μs |

¹⁾ depending on thermal properties of assembly

²) not subject to production test - verified by design/characterization

³⁾ allowed number of short circuits: <1000; time between short circuits: >1s.

Static Characteristics (tested on wafer), T_{vi} =25 °C

| Parameter | Symbol | Conditions | Value | | | Unit |
|--------------------------------------|----------------------|---|-------|------|------|------|
| | Cymbol | | min. | typ. | max. | |
| Collector-Emitter breakdown voltage | V _{(BR)CES} | V _{GE} =0V , <i>I</i> _C =4 mA | 650 | | | |
| Collector-Emitter saturation voltage | V _{CEsat} | V _{GE} =15V, <i>I</i> _C =75A | 0.93 | 1.45 | 1.77 | V |
| Gate-Emitter threshold voltage | $V_{\rm GE(th)}$ | $I_{\rm C}$ =1.2mA , $V_{\rm GE}$ = $V_{\rm CE}$ | 5.1 | 5.8 | 6.4 | |
| Zero gate voltage collector current | I _{CES} | V _{CE} =650V , V _{GE} =0V | | | 3.8 | μA |
| Gate-Emitter leakage current | I _{GES} | V _{CE} =0V , V _{GE} =20V | | | 600 | nA |
| Integrated gate resistor | r _G | | | 4 | | Ω |

Electrical Characteristics (not subject to production test - verified by design / characterization)

| Parameter | Symbol | Conditions | Value | | | Unit |
|--------------------------------------|--------------------|---|-------|------|------|------|
| Falameter | Symbol | | min. | typ. | max. | |
| Collector Emitter acturation voltage | V | V _{GE} =15V, <i>I</i> _C =75A, | | tha | | V |
| Collector-Emitter saturation voltage | V _{CEsat} | <i>T</i> _{vj} =175 °C | | tbd | | v |
| Input capacitance | Cies | V _{CE} =25V, | | 4620 | | |
| | | V _{GE} =0V, <i>f</i> =1MHz | | | | pF |
| Reverse transfer capacitance | C _{res} | $T_{\rm vj}$ =25 °C | | 137 | | |



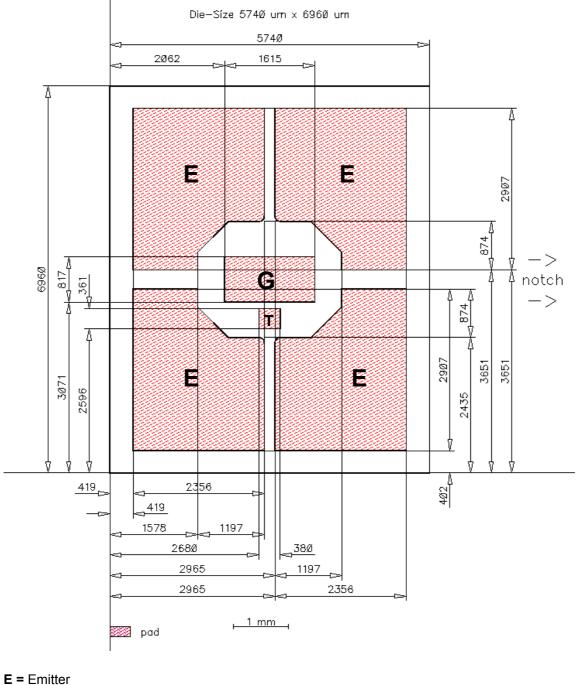
Further Electrical Characteristic

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

| This chip data sheet refers to the device data sheet | tbd | tbd |
|--|-----|-----|
|--|-----|-----|



Chip Drawing



- G = Gate
- T = Test pad do not contact



Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

| Version | Subjects (major changes since last revision) | Date |
|---------|--|------|
| | | |
| | | |

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